



The 9th International Symposium on Measurement Technology and Intelligent Instruments ISMTII-2009 Saint-Petersburg, Russia 29 June – 2 July 2009

ISMTII-2009 will focus in measurement science and metrology, micro- and nano- measurements, novel measurements and diagnostic technologies, including nondestructive and dimensional inspection, using X-Ray, optical and terahertz radiation for science, industry and biomedicine, as well as in intelligent measuring instruments, characterization of materials and measurements for the humanitarian fields. Participation in this Symposium located in famous Saint-Petersburg, which from its foundation is a unique communication bridge between countries of all continents, is a very good opportunity for the exchange by experience, information and knowledge between the specialists from different fields.

Symposium Homepage: tdisie.nsc.ru/ismtii2009

Organized by

International Committee on Measurements and Instrumentation (ICMI)

D.I. Mendeleev Institute for Metrology (VNIIM)

Saint-Petersburg State University of Information Technologies, Mechanics and Optics (SPbSU ITMO)

Saint-Petersburg State Polytechnical University (SPbSPTU), Russia



Russian Academy of Sciences, Siberian Branch (SB RAS)
Technological Design Institute of Scientific Instrument Engineering (TDI SIE)



Scientific and Industrial Corporation «Vavilov State Optical Institute»



D.S. Rozhdestvensky Optical Society, Russia



In cooperation with

- International Scientific-Technical Society of Instrument Engineers and Metrologists (ISTS IEM), Russia
- Federal Agency on Technical Regulating and Metrology, Russia
- Laser Association, International Scientific-Technical Organization, Russia
- Metrological Academy of Russia
- A.M. Prokhorov Academy of Engineering Sciences, Siberian Branch, Russia

At the assistance of

- Russian Foundation for Basic Research (RFBR)
- Hon Hai Technology Precision Ind., Co., Ltd, Taiwan, China
- West-Siberian Railroad of the Russian Federation

Sponsored by

- Sartorius Company, Germany
- SIOS Company, Germany

Endorsed by

The Chairmen of Technical Committees TC2, TC7 and TC14 of IMEKO (International Measurement Confederation)

Registration Fee

Registration fee includes: Attendance at Technical Program, Welcome Party, Lunches (3 days), Coffee breaks, Farewell Party, Trip of the city, Hard copy of Proceedings (except accompanying persons), Disc with Proceedings.

Participants: 300 Euro

Students: 150 Euro

Accompanying Person: 200 Euro

Technical Tours and visits to Hermitage museum, Petrodvorets and Tsarskoe selo and so on will be organized on June 30, July 2 and 3 for additional fee. As for Post-Symposium Tour, the visit to Moscow is under discussion.

The venue of the Symposium is Saint-Petersburg

The end of June and the beginning of July in Saint-Petersburg are the best summer periods of white nights.

Important Dates

- ✓ Submission of abstracts: **September 1, 2008**
- ✓ Notification of abstracts acceptance: **November 1, 2008**
- ✓ Submission of manuscripts: **February 1, 2009**
- ✓ Notification of manuscripts acceptance: **March 15, 2009**



Symposium Scope

- 1. General Problems of Measurement**, including:
 - Fundamental Problems
 - Emerging Physical Principles of Measurements
 - Uncertainty, Traceability, Calibration
- 2. Micro- Nano- Measurements and Metrology**, including:
 - 3D Micro / Nano Measurement and Fabrication Techniques
 - Micro / Nano- Sensors in Biomedicine
 - Measurements for Micro-Optics and Nano-Photonics
- 3. Optical and X-Ray Tomography and Interferometry**
- 4. Measurements for Geometrical and Mechanical Quantities**, including:
 - Dimensional and Surface Measurements
 - 3D Inspection and Metrology
 - Measurement of Motion Parameters
- 5. Terahertz Technologies for Science, Industry, Medicine, Biology**
- 6. Novel Measurement and Diagnostic Methods**, including:
 - Femtosecond Laser Pulses Measurement Techniques
 - Advanced Semiconductor Optoelectronic Sensors and Instruments
 - Nonlinear Optical Instruments Applied for Industry
 - Optical Fiber Measurements and Sensors
 - Ultra Precision Wave Front Measurement Techniques
 - Remote Sensing and Signal Processing
- 7. Intelligent Measuring Instruments and Systems for Industry and Transport**, including:
 - Algorithms and Software
 - Metrological Assurance In-Process and On-Line
 - Metrological Self-Diagnostics
 - Methods for Testing of Long Lifetime Sensors
- 8. Measurements and Metrology for the Humanitarian Fields**
- 9. Metrology and Characterization of Materials**, including:
 - Hardness Measurements
 - Analytical Measurements
- 10. Education in Measurement Science**

Symposium Chairman
Prof. Yuri Chugui, Russia

Honorary Chairman
Prof. Zhu Li, China

Chairs of the International Program Committee
Prof. Vladimir Vasiliev, Russia
Prof. Yuri Chugui, Russia

Chair of Organization Committee, Symposium Scientific Secretary
Dr. Mikhail Stupak, Russia

Co-Chair of Organization Committee
Dr. Vladimir Arpishkin, Russia



Keynote Plenary and Section Invited Speakers

1. Academician Gennady Kulipanov, Budker Institute of Nuclear Physics, SB RAS, Russia
2. Prof. Malgorzata Kujawska, Warsaw University of Technology, Poland
3. Prof. Mitsuo Takeda, The University of Electro-Communications, Japan
4. Academician Alexander Aseev, Institute of Semiconductor Physics, SB RAS, Russia
5. Prof. Gerd Jäger, Technical University of Ilmenau, Germany
6. Prof. Peter Rolfe, Oxford BioHorizos Ltd, UK
7. Prof. Hidenori Mimura, Shizuoka University, Japan
8. Prof. Tilo Pfeifer and Prof. Robert Schmitt, Fraunhofer-Institute for Production Technology, Germany
9. Corresp. member of RAS Nikolay Kolchanov, Institute of Cytology and Genetics, SB RAS, Russia
10. Prof. Ga-Lane Chen, HON HAI Technology Group, Taiwan, China
11. Prof. Boris Chichkov, Laser Zentrum Hannover e.V., Germany
12. Dr. Andrew Yacoot, National Physical Laboratory, UK
13. Prof. Shulian Zhang, Tsinghua University, China
14. Dr. Richard Leach, National Physical Laboratory, UK
15. Prof. Albert Weckenmann, University Erlangen-Nuremberg, Germany
16. Prof. Yasuhiro Takaya, Osaka University, Japan
17. Prof. Vladimir Lukin, Institute of Atmospheric Optics, SB RAS, Russia
18. Dr. Michael Krystek, Physikalisch-Technische Bundesanstalt, Germany
19. Dr. Jürgen Kompenhans, Institute of Aerodynamics and Flow Technology, Germany
20. Prof. Junfeng Song, National Institute of Standards and Technology, USA



Publications

All accepted papers will be published in ISMTII-2009 Proceedings.

Some selected papers after revision will be proposed for publishing in «Measurement Science and Technology», «Key Engineering Materials» and «Measurement Techniques» Journals (publication cost will be informed).

Technical Tours

- D.I. Mendeleyev Institute for Metrology (VNIIM)
- Scientific and Industrial Corporation «Vavilov State Optical Institute»
- Saint-Petersburg State University of Information Technologies, Mechanics and Optics (SPbSU ITMO)

Social program

- Visits to
- Hermitage museum
 - Peterhof (Petrodvorets)
 - Pushkin (Tsarskoe selo)
 - St. Isaac's Cathedral and so on

Technical Sessions and Round Table

Symposium will include Keynote Speeches and Session Invited Speeches, Oral and Poster presentations. Discussions at the Round Table will be organized.

Contacts

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